

FORM PTO 1449 ( <i>modified</i> ) <b>U.S. DEPARTMENT OF COMMERCE</b> <b>PATENT AND TRADEMARK OFFICE</b> <b>LIST OF REFERENCES CITED BY APPLICANT(S)</b> <i>(Use several sheets if necessary)</i> Date Submitted to PTO: January 29, 2004			ATTY DOCKET NO. 2004-0145		SERIAL NO. <del>NEW</del> 60/766,565		
			APPLICANT Yoko SUZUKI et al.				
			FILING DATE January 29, 2004		GROUP 1724		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>Mly</i>	AA	5,346,518	9/1994	Baseman et al.			
	AB	6,040,680	3/2000	Toya et al.			
	AC	5,380,503	1/1995	Fujii et al.			
	AD	2001/0011640	8/2001	Suzuki et al.			
	AE	4,967,295	10/1990	Yamauchi et al.			
	AF	6,436,849	8/2002	Hasunuma et al.			
	AG	4,471,716	9/1984	Milliren			
	AH	5,207,548	5/1993	Suffel			
<i>Mly</i>	AI	5,255,797	10/1993	Kos			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
<i>Mly</i>	AJ	2000-174109	6/2000	JP			
	AK	9-29020	2/1997	JP			
	AL	6-291177	10/1994	JP			
	AM	7-94577	4/1995	JP			
	AN	617573A		EP			
	AO	69401023C		DE			
	AP	11-195699	7/1999	JP			
	AQ	2000-223554	8/2000	JP			
<i>Mly</i>	AR	11-314703	11/1999	JP			
OTHER DOCUMENT(S) ( <i>Including Author, Title, Date, Pertinent Pages, Etc.</i> )							
<i>Mly</i>	AS	Shoko ITO et al., "Wafer ambient control for Agile FAB", 0-7803-6731-6/01/\$10.00©2001 IEEE, pgs. 121-124.					
EXAMINER	<i>Mly</i>			DATE CONSIDERED		6/2/05	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of form with next communication to applicant.

FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. 2004-0145	SERIAL NO. NEW 10/766,585			
			APPLICANT Yoko SUZUKI et al.				
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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>ML</i>	AA	5,749,469	5/1998	Williams			
<i>ML</i>	AB	6,364,922	4/2002	Tanaka et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
<i>ML</i>	AC	11-40207	2/1999	JP			
	AD	381356B		TW			
	AE	0560379A1	9/1993	EP			
	AF	6-29373	2/1994	JP			
	AG	69304570C		DE			
	AH	2000-311936	11/2000	JP			
	AI	7-293956	11/1995	JP			
	AK	7-125806	5/1995	JP			
	AL	3-143518	6/1991	JP			
	AM	11-274282	10/1999	JP			
<i>ML</i>	AN	2000-253596	9/2000	JP			
<i>ML</i>	AO	1297882A1	4/2003	EP			
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AP						
	AQ						
	AR						
EXAMINER	<i>M. L. Williams</i>			DATE CONSIDERED	<i>06/02/05</i>		

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